

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1731		SERIAL NO. <del>Unknown</del> 09/932,003	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Cem Basceri		GROUP 2813	
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
jk	AA	5,256,455	10/26/93	Numasawa			
	AB	5,459,635	10/17/95	Tomozawa et al.			
	AC	5,596,214	01/21/97	Endo			
	AD	5,618,761	04/08/97	Eguchi et al.			
	AE	5,731,948	03/24/98	Yializis et al.			
	AF	5,776,254	07/07/98	Yuuki et al.			
	AG	5,783,253	07/21/98	Roh			
	AH	5,798,903	8/25/98	Dhote et al.			
	AI	6,043,526	3/28/00	Ochiai			
	AJ	6,046,345	04/04/00	Kadokura et al.			
AK	6,078,492	06/20/00	Huang et al.				
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
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jk	AL	EP 0 855 735 A2	29.07.98	Europe (Applied Materials, Inc.)			
	AM	EP 0 957 522 A2	17.11.99	Europe (Matsushita Electric Industrial Co. Ltd.)			
	AN	WO 98/39497	09/11/98	WIPO (Simpson, et al.)			
	AO	0 474 140 A1	08/30/91	Europe (Kamiyama)			
	AP	WO 99/64645	12/16/99	WIPO (Narwankur, et al.)			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
jk	AR	Steve Bilodeau et al., <i>Composition Dependence of the Dielectric Properties of MOCVD Ba<sub>1-x</sub>Sr<sub>x</sub>TiO<sub>3</sub></i> , pp. 1-21 (MRS Fall Meeting 12/01/94).					
jk	AS	Steve M. Bilodeau et al., <i>MOCVD BST for High Density DRAM Applications</i> (Preprint for SEMICON/WEST 07/12/95), 2 pages.					
jk	AT	Y-C Choi et al., Abstract, <i>Improvements of the Properties of Chemical-Vapor-Deposited (Ba,Sr)TiO<sub>3</sub> Films Through Use of a Seed Layer</i> , 36 JPN. J. APPL. PHYS. Pt. 1, No. 11, pp. 6824-6828 (1997)					
EXAMINER				DATE CONSIDERED 12/21/01			
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
YS	AA	6,153,898	11/28/00	Watanabe et al.			
	AB	6,037,205	03/14/00	Huh, et al.			
	AC	5,470,398	11/28/95	Shibuya, et al.			
	AD	5,254,505	10/19/93	Kamiyama			
	AE	6,156,638	12/05/00	Agarwal et al.			
YS	AF	6,165,834	12/26/00	Agarwal et al.			
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YS	AR		Chung Ming Chu et al., Abstract, <i>Electrical properties and crystal structure of (Ba,Sr)TiO<sub>3</sub> films prepared at low temperatures</i>				
			on a LaNiO <sub>3</sub> electrode by radio-frequency magnetron ...., 70 APPLIED PHYSICS LETTERS No. 2, pp. 249-251 (1997).				
YS	AS		Kazuhiro Eguchi et al., Abstract, <i>Chemical vapor deposition of (Ba,Sr)TiO<sub>3</sub> thin films for application in gigabit scale</i>				
			dynamic random access memories, 14 INTEGRATED FERROELECTRICS Nos. 1-4, Pt. 1, pp. 33-42 (1997).				
YS	AT		Q.X. Jia et al., Abstract, <i>Structural and dielectric properties of Ba<sub>0.5</sub>Sr<sub>0.5</sub> thin films with an epi-RuO<sub>2</sub> bottom electrode.</i>				
			19 INTEGRATED FERROELECTRICS Nos. 1-4, pp. 111-119 (1998).				
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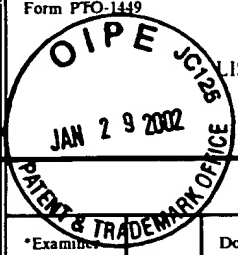
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yjs	AR		Takaaki Kawahara et al., (Ba, Sr)TiO <sub>2</sub> Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes, 35 JPN. J. APPL. PHYS. Pt. 1, No. 9B, pp. 4880, 4883 (1996).				
	AS		Rajesh Khamankar et al., A Novel Low-Temperature Process for High Dielectric Constant BST Thin Films for ULSI DRAM Applications, Microelectronics Research Center, Univ. of Texas at Austin, TX (Undated), 2 pages.				
SW	AT		Yong Tae Kim et al., Abstract, Advantages of RuO <sub>2</sub> bottom electrode in the dielectric and leakage characteristics of (Ba,Sr)TiO <sub>2</sub> capacitor, 35 JPN. J. APPL. PHYS. Pt. 1, No. 12A, pp. 6153-6156 (1996).				
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
y y y y y	AR		S.H. Paek et al., Abstract, <i>Characterization of MIS capacitor of BST thin films deposited on Si by RF magnetron sputtering</i> .			
			Ferroelectric Thin Films V. Symposium, San Francisco, CA, pp. 33-38 (April 7, 1995).			
	AS		N. Takeuchi et al., Abstract, <i>Effect of firing atmosphere on the cubic-hexagonal transition in Ba<sub>0.99</sub>Sr<sub>0.01</sub>TiO<sub>3</sub></i> , 98 NIPPON			
			SERAMIKKUSU KYOKAI GAKUJUTSU RONBUNSHI No. 8, pp. 836-839 (1990).			
	AT		H. Yamaguchi, et al., Abstract, <i>Reactive coevaporation synthesis and characterization of SrTiO<sub>3</sub>-BaTiO<sub>3</sub> thin films</i> , IEEE			
			International Symposium on Applications of Ferroelectrics, Greenville, SC, pp. 285-288 (August 2, 1992).			
EXAMINER			DATE CONSIDERED			
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
48	AR		S. Yamamichi et al., Abstract, <i>Ba + Sr/Ti ratio dependence of the dielectric properties for (Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> thin films prepared by ion beam sputtering</i> , 64 APPLIED PHYSICS LETTERS No. 13, pp. 1644-1646 (1994).				
	AS		M. Yamamuka et al., Abstract, <i>Thermal-Desorption Spectroscopy of (Ba,Sr)TiO<sub>3</sub> Thin-Films Prepared by Chemical-Vapor-Deposition</i> , 35 JPN. J. OF APPL. PHYS. Pt. 1, No. 2A, pp. 729-735 (1996).				
b	AT		Arai T., et al.: "Preparation of SrTiO <sub>3</sub> Films on 8-Inch Wafers. . ." Jap. Journal of Applied Physics. Vol. 35, No. 9B, Part 01, 09/01/96, Pgs. 4875-4879.				
EXAMINER  [Signature]				DATE CONSIDERED  12/2/01			
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ll	AA	09/388,063		Agarwal et al.			August 30, 1999
	AB	09/476,516		Basceri			January 3, 2000
	AC	09/580,733		Basceri			May 26, 2000
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		Kim, et al.: "Structural and Electrical Properties. . ." Applied Physics Letters, US, American Institute of Physics Vol. 65, No. 15, 10/10/94,				
			Pgs. 1955 - 1957.				
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				FILING DATE August 17, 2001		GROUP 2831	
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yk	AA 5,834,060	11/98	Kawahara et al.				
	AB 5,972,430	10/99	DiMeo, Jr. et al.				
	AC 6,127,218	10/00	Kang				
	AD 6,277,436 B1	08/01	Stauf et al.				
	AE 6,245,652 B1	06/01	Gardner et al.				
jc	AF 6,126,753	10/00	Shinriki et al.				
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AR		Basceri, Cem et al., "The Dielectric Response as a Function of Temperature and Film Thickness of Fiber-Textured (Ba,Sr)TiO <sub>3</sub> Thin Films Grown by Chemical Vapor Deposition", J. Appl. Phys. 82(5), Sept. 1, 1997, pp. 2497-2504.					
AS							
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yk				12/2/02			
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U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	App. SN 09/652,907 (as filed and amended)		C. Basceri et al.			08/31/00
AB	App. SN 09/776,217 (as filed and amended)		C. Basceri			02/02/01
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Sheet 1 of 2

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Form <b>PTOL 44</b>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1731		SERIAL NO. 09/932,003	
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ya	AR		DISSERTATION: Basceri, Cem, "Electrical and Dielectric Properties of (Ba,Sr)TiO <sub>3</sub> Thin Film Capacitors for Ultra High Density				
			Dynamic Random Access Memories", 1997, 171 pgs.				
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U.S. PATENT DOCUMENTS

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MP	AA App. SN 09/905,286 (as filed and amended)		C. Basceri et al.			07/13/01
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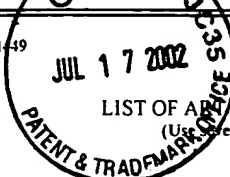
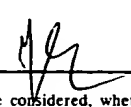
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4	AA	6,238,734 B1	05/01	Senzaki et al.			RECEIVED JUL 23 2002 TECHNOLOGY CENTER 2800	
	AB	6,146,907	11/00	Xiang et al.				
	AC	6,323,057 B1	11/01	Sone				
ML	AD	6,362,068 B1	03/02	Summerfelt et al.				
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